

Call for participation

WORKSHOP ON OPTICAL SURFACE ANALYSIS METHODS FOR NANOSTRUCTURED LAYERS

Organised by BAM, HZB, Accurion

October 10, 2019

BAM Branch Adlershof
Konferenzbereich
Haus 8.05, Raum 201 und 202
Richard-Willstätter-Straße 11
12489 Berlin

The Workshop on optical surface analysis methods for nanostructured layers will take place in the conference centre at the BAM facility in Berlin-Adlershof on 10th of October, 2019. The workshop is intended to bring together scientists and applications experts in the fields of nano-analysis of layers and surfaces with a multitude of different methods. The programme will cover investigation of structural parameters of layers by means of optical, X-ray spectroscopic, electron microscopic, and surface scanning methods.

Energy storage and conversion require nano-structured functional layers. Therefore, nanomaterials use in energy applications will be a main focus in this event.

Topics:

- Surface analytical chemistry
- Surface and layer analysis with optical, x-ray, and particle beam techniques
- Mapping and imaging spectroscopic methods
- Hybrid spectroscopic methods for surface analysis, e.g. spectroscopic ellipsometry combined with SEM
- Data evaluation and data fusion methodologies for analysing nano- and mesostructured materials systems
- Optimisation of materials for energy applications

The workshop participation is free of charge, but registration is required, due to limited capacity. Please register via e-mail to thin-films@bam.de.

This workshop is organised in conjunction with the HyMET-Project